Sheet 1 of 1

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY, DOCKET NO.		SERIAL NO.			
		PATENT AND I	RADEIWARK OFFICE			10/661,299			
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT				APPLICANT					
(Use several sheets if necessary)				Howard Hao Chen et al.					
				FILING DATE		GROUP ART UNIT			
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U.S. PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS		DATE OPRIATE	
BX		5,154,661	10/13/92	Higgins	62	3.3	7/10/91		
BU		5,259,737	11/9/93	Kamisuki et al.	417	322 7/2/91			
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BU		6,080,608	6/27/00	Nowak	438	151	8/6/98		
FOREIGN PATENT DOCUMENTS									
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		NUMBER					YES	NO	
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OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)									
Ви		Larry Gilg et al., "Die Products: ideal IC packaging for demanding applications", Electronic Design, December 23, 2002, pp. 47-50.							
BU			M. Armacost et al., "Plasma-etching processes for ULSI semiconductor circuits", IBM J. Res. Develop., Vol. 43, No. 1/2, January/March 1999, pp. 39-72.						
EXAMINER DATE CONSIDERED									
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									
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